Notice of References Cited Application/Control No. Applicant(s)/Patent Under Reexamination LEE, YONG-HEE Examiner Khai M. Nguyen Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,468,790	08-1984	Hofelt, Martijn H. H.	375/245
	В	US-4,862,169	08-1989	van Bavel et al.	341/143
	С	US-5,030,952	07-1991	Ledzius et al.	341/143
	D	US-5,061,928	10-1991	Karema et al.	341/143
	E	US-6,300,890	10-2001	Okuda et al.	341/143
	F	US-6,515,607	02-2003	Liu et al.	341/143
	G	US-4,876,543	10-1989	van Bavel, Nicholas R.	341/143
	н	US-4,920,544	04-1990	Endo et al.	375/243
	1	US-5,298,900	03-1994	Mauthe et al.	341/143
	J	US-5,148,167	09-1992	Ribner, David B.	341/143
	К	US-5,446,460	08-1995	Cabler, Carlin D.	341/143
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	α					
	R					
	Ø					
	۲					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	x	·				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.